

Notice of References Cited	Application/Control No. 10/073,192	Applicant(s)/Patent Under Reexamination SHEN, WEN CHAO	
	Examiner N. Bhat	Art Unit 1764	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,830,661	12-2004	Land, Glenn E.	202/83
*	B	US-6,294,054	09-2001	Sutter, Douglas E.	202/176
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/073,192	Applicant(s)/Patent Under Reexamination SHEN, WEN CHAO	
	Examiner N. Bhat	Art Unit 1764	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,830,661	12-2004	Land, Glenn E.	202/83
*	B	US-6,294,054	09-2001	Sutter, Douglas E.	202/176
*	C	US-2004/0129723 A1	07-2004	Meder et al.	222/113
*	D	US-5,511,388 A	04-1996	Taylor et al.	62/389
*	E	US-5,567,308 A	10-1996	Visser, Timon J.	210/232
*	F	US-5,200,039 A	04-1993	Weber et al.	202/197
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.